


<b>Search Notes</b>  	<b>Application/Control No.</b>  10717741	<b>Applicant(s)/Patent Under Reexamination</b>  CONROY ET AL.
	<b>Examiner</b>  Keefer, Michael E	<b>Art Unit</b>  2454

SEARCHED			
Class	Subclass	Date	Examiner
709	206 (updated 2/26/2009)	6/28/2007	MEK

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Search	6/28/2007	MEK
Google Search	6/28/2007	MEK
ACM Search	6/29/2007	MEK
IEEE Xplore Search	6/29/2007	MEK
EAST Search	9/13/2008	MEK
Consulted Primary Examiner Dustin Nguyen, Class 709	2/26/2009	MEK
Consulted Examiner Hassan Phillips, Class 709	2/26/2009	MEK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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